

Docket No.: PEK-In1163 D

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Wilhelm Asam et al.
Div. of Applic. No. : 10/200,934, filed July 23, 2002
Div. filed : January 2, 2004
Title : Method for Detecting the Reliability of Integrated
Semiconductor Components at High Temperatures
Examiner : Scott R. Wilson Group Art Unit: 2826

Hon. Commissioner for Patents
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. 1.98, the following patents and/or publications are cited herewith:

U. S. Patent No. 5,309,090 (Lipp), dated May 3, 1994;

U.S. Patent No. 5,751,015 (Corbett et al.), dated May 12, 1998;

U.S. Patent No. 5,436,494 (Moslehi), dated July 25, 1995;

U.S. Patent No. 5,406,212 (Hashinaga et al.), dated April 11, 1995;

German Patent DE 198 41 202 C1 (Gärtner et al.), dated March 2, 2000, Temperature Sensor;

Meijer, G.: "Thermal Sensor Based on Transistors", Elsevier Sequoia, 1986, pp. 103-125;

Shideler, J. et al.: "A Systematic Approach to Wafer Level Reliability", Solid State Technology, March 1995, pp. 47, 48, 50, 52, 54.

The above-mentioned references were cited in an *Information Disclosure Statement* dated August 16, 2003, in parent application No. 10/200,934.

U.S. Patent No. 4,356,379 (Graeme), dated October 26, 1982;

U.S. Patent No. 5,414,370 (Hashinaga et al.), dated May 9, 1995;

Anonymous: "Method to Determine Substrate Potential and Chip Temperature", Research Disclosure, March 1990, No. 311, New York, XP-000104454;

R.A. Bianchi et al.: "CMOS-Compatible Temperature Sensor with Digital Output for Wide Temperature Range Applications", Microelectronics Journal, No. 31, 2000, pp. 803-810;

European Search Report, dated May 26, 2003.

The above-mentioned references were cited in an Information Disclosure Statement dated June 13, 2003, in parent application No. 10/200,934.

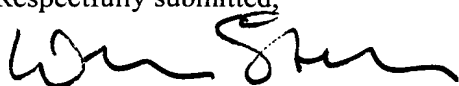
U.S. Patent No. 5,195,827 (Audy et al.), dated March 23, 1993;

U.S. Patent No. 5,309,090 (Lipp), dated May 3, 1994;

U.S. Patent No. 5,280,327 (Buks), dated January 18, 1994.

The above-mentioned references were cited in Office action dated June 19, 2003, in parent application No. 10/200,934.

Respectfully submitted,



For Applicants

Date: January 2, 2004

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FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: Divisional of Applic. No. PEK-In1163 D 10/200,934 Applicant Wilhelm Asam et al. Filing Date of Divisional Group Art Unit January 2, 2004 2826			
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	5,309,090	05/94	Lipp			
	B	5,751,015	05/98	Corbett et al.			
	C	5,436,494	07/95	Moslehi			
	D	5,406,212	04/95	Hashinaga et al.			
	E	4,356,379	10/82	Graeme			
	F	5,414,370	05/95	Hashinaga et al.			
	G	5,195,827	03/93	Audy et al.			
	H	5,280,327	01/94	Buks			
	I						
FOREIGN PATENT DOCUMENT							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J						
	K						
	L						
	M						
	N						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
		Meijer, G.: "Thermal Sensor Based on Transistors", Elsevier Sequoia, 1986, pp. 103-125.					
		Shideler, J. et al.: "A Systematic Approach to Wafer Level Reliability", Solid State Technology, March 1995, pp. 47, 48, 50, 52, 54.					
EXAMINER				DATE CONSIDERED			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: PEK-In1163 D Divisional of Applic. No. 10/200,934 Applicant Wilhelm Asam et al. Filing Date of Divisional Group Art Unit January 2, 2004 2826			
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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
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	K						
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
		Anonymous: "Method to Determine Substrate Potential and Chip Temperature", Research Disclosure, March 1990, No. 311, New York, XP-000104454.					
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